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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1 of 1

Complete If Known	
Application Number	10/604,984
Filing Date	28 August 2003
First Named Inventor	Razak Hossain
Art Unit	2825
Examiner Name	Naum Levin
Attorney Docket Number	03-LJ-011

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[2]
NL		DE, VIVEK et al., Techniques for Leakage Power Reduction, Design of High-Performance Microprocessor Circuits, IEEE Press, Chap. 3, pp. 46-62, 2001	
NL		ALOUL, PADI A., et al., "Robust SAT-Based Search Algorithm for Leakage Power Reduction", International Workshop on Power and Timing Modeling, Optimization and Simulation, Seville, Spain, 2002	

Examiner Signature	Naum Levin /Naum Levin/	Date Considered	10/13/2006

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

2/18/06

SANKARALINGAM, R., et al., "Reducing Test Power During Test Using Programmable Scan Chain Disable," XP010587990, Proceedings of the First IEEE International Workshop on Electronic Design, Test and Applications, January 29, 2002, pages 159-163.

WANG, S., "Generation of Low Power Dissipation and High Fault Coverage Patterns for Scan-Based BIST," XP010609814, ITC International Test Conference, Paper 29.3, Oct. 7-10, 2002, pages 834-843.

SINANOGLU, O., et al, "Test Power Reduction Through Minimization of Scan Chain Transitions," XP-002306228, Proceedings of the 20th IEEE VLSI Test Symposium, April 28, 2002, pages 166-171.

Applicant hereby expressly reserves the right to swear behind the effective dates of any of the above Patents and to question the relevance and materiality of the Patents and Publications listed herein, in whole, in part, or in combination, subsequent to filing this Information Disclosure Statement.

In accordance with 37 C.F.R. 1.97(e), the undersigned certifies that each item of information contained in the Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Information Disclosure Statement.

Further, pursuant to 37 C.F.R. § 1.97(e) and the above statements, no fee is believed to be due for the filing of this Information Disclosure Statement.

Respectfully submitted,

DAVIS MUNCK, P.C.

Date: Feb. 15 2005

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Applicant must present form PTO/SB/08 for the future consideration.

Naum Levin /Naum Levin/ 10/24/2006